

# Sukeshwar Kannan

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/9147708/publications.pdf>

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5  
papers

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citations

2682572

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docs citations

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times ranked

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citing authors

#	ARTICLE	IF	CITATIONS
1	Impact of Electrostatic Coupling and Wafer-Bonding Defects on Delay Testing of Monolithic 3D Integrated Circuits. ACM Journal on Emerging Technologies in Computing Systems, 2017, 13, 1-23.	2.3	28
2	Impact of wafer-bonding defects on Monolithic 3D integrated circuits. , 2016, , .		10
3	A Design-for-Test Solution Based on Dedicated Test Layers and Test Scheduling for Monolithic 3-D Integrated Circuits. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2019, 38, 1942-1955.	2.7	10
4	A Design-for-Test Solution for Monolithic 3D Integrated Circuits. , 2017, , .		8
5	Built-in Self-Test and Fault Localization for Inter-Layer Vias in Monolithic 3D ICs. ACM Journal on Emerging Technologies in Computing Systems, 2022, 18, 1-37.	2.3	2